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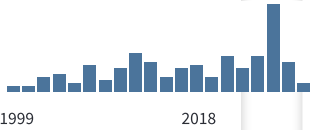
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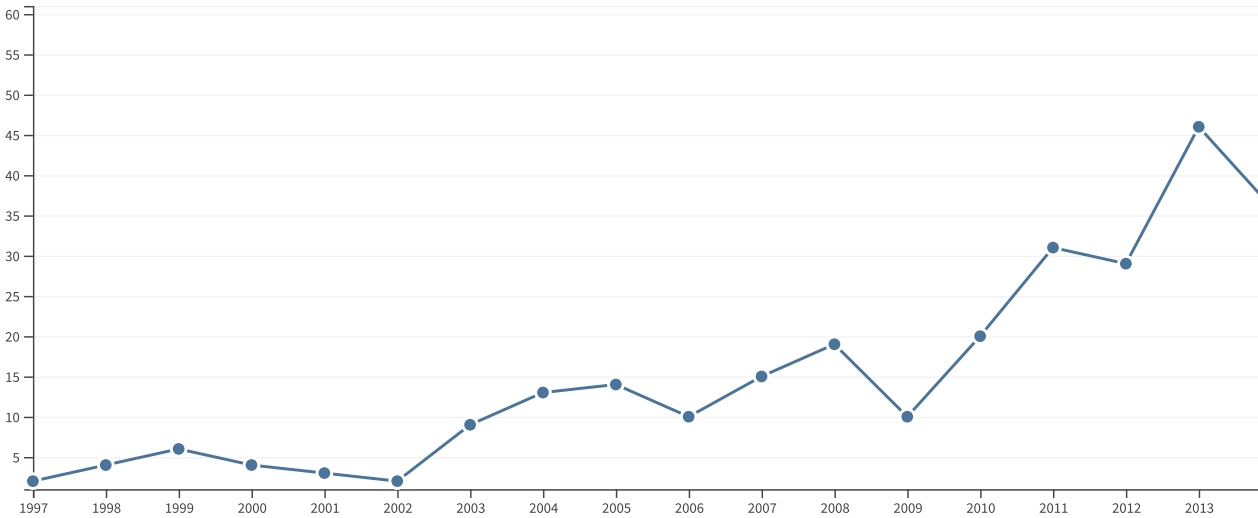
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<input type="checkbox"/>	1.	Comprehensive Device Reliability and Oxide Traps Distribution Analysis by the Low Frequency Noise in Ultra-Thin Body SOI (UTBSOI) MOSFETs	By: Lin, Cheng-Li; Soh, Chun-Hung; Yeh, Wen-Kuan; et al. Conference: IEEE 8th Nanotechnology Materials and Devices Conference (NMDC) Location: Natl Cheng Kung Univ, Tainan, TAIWAN Date: OCT 06-09, 2013 Sponsor(s): IEEE; IEEE NANO 2013 IEEE 8TH NANOTECHNOLOGY MATERIALS AND DEVICES CONFERENCE (NMDC) Book Series: IEEE Nanotechnology Materials and Devices Conference Pages: 1-4 Published: 2013							
<input type="checkbox"/>	2.	Substrate noise-coupling characterization and efficient suppression in CMOS technology	By: Yeh, WK; Chen, SM; Fang, YK IEEE TRANSACTIONS ON ELECTRON DEVICES Volume: 51 Issue: 5 Pages: 817-819 Published: MAY 2004	1	1	2	3	0	25	1.67
<input type="checkbox"/>	3.	Impacts of notched-gate structure on contact etch stop layer (CESL) stressed 90-nm nMOSFET	By: Lin, Chien-Ting; Fang, Yean-Kuen; Yeh, Wen-Kuan; et al. IEEE ELECTRON DEVICE LETTERS Volume: 28 Issue: 5 Pages: 376-378 Published: MAY 2007	0	3	0	2	0	21	1.75
<input type="checkbox"/>	4.	Optimum halo structure for sub-0.1 mu m CMOSFETs	By: Yeh, WK; Chou, JW IEEE TRANSACTIONS ON ELECTRON DEVICES Volume: 48 Issue: 10 Pages: 2357-2362 Published: OCT 2001	0	0	2	0	0	20	1.11
<input type="checkbox"/>	5.	Reliability Improvement of 28-nm High-k/Metal Gate-Last MOSFET Using Appropriate Oxygen Annealing	By: Yang, Yi-Lin; Zhang, Wenqi; Cheng, Chi-Yun; et al. IEEE ELECTRON DEVICE LETTERS Volume: 33 Issue: 8 Pages: 1183-1185 Published: AUG 2012	4	4	1	3	1	17	2.43
<input type="checkbox"/>	6.	Effects of Fin Width on Device Performance and Reliability of Double-Gate n-Type FinFETs	By: Lin, Cheng-Li; Hsiao, Po-Hsiu; Yeh, Wen-Kuan; et al. IEEE TRANSACTIONS ON ELECTRON DEVICES Volume: 60 Issue: 11 Pages: 3639-3644 Published: NOV 2013	2	2	5	4	2	15	2.50
<input type="checkbox"/>	7.	Relationship between wafer edge design and its ultimate mechanical strength	By: Chen, Po-Ying; Tsai, Ming-Hsing; Yeh, Wen-Kuan; et al. MICROELECTRONIC ENGINEERING Volume: 87 Issue: 11 Pages: 2065-2070 Published: NOV 2010	0	2	2	4	0	15	1.67
<input type="checkbox"/>	8.	The Improvement of High-k/Metal Gate pMOSFET Performance and Reliability Using Optimized Si Cap/SiGe Channel Structure	By: Yeh, Wen-Kuan; Chen, Yu-Ting; Huang, Fon-Shan; et al. IEEE TRANSACTIONS ON DEVICE AND MATERIALS RELIABILITY Volume: 11 Issue: 1 Pages: 7-12 Published: MAR 2011	3	1	0	1	0	14	1.75
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IEEE TRANSACTIONS ON ELECTRON DEVICES

Volume: 51 Issue: 3 Pages: 324-331

Published: MAR 2004


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